

# WAVEFRONT SENSING WITH A THIN DIFFUSER: APPLICATION TO SUPER-LOCALIZATION

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We recently proposed and implemented a broadband, compact, and low-cost WaveFront Sensing (WFS) scheme by simply placing a thin diffuser in the close vicinity of a camera [1]. The local wavefront gradient is determined from local translations of the speckle pattern. The translation vector map is computed using a fast-diffeomorphic image registration algorithm and integrated to reconstruct the wavefront profile. The simple translation of speckle grains under local wavefront tip/tilt is ensured by the so-called “memory effect” of the diffuser [2]. We also demonstrated that the method allows quantitative phase-imaging, since the unique signature of the speckle pattern avoids reconstruction artifacts encountered in periodic mask - based WFS(see Fig 1).. After a detailed description of the WFS principle, we will demonstrate the potential of the technique for 3D nanoparticle localization. In the context of superlocalization-based microscopies, we will show that the high localization precision of the method (0.3x0.3x3nm) makes this device a valuable add-on for estimating sample drifts and enhance the performances of super-resolution microscopy techniques [3].

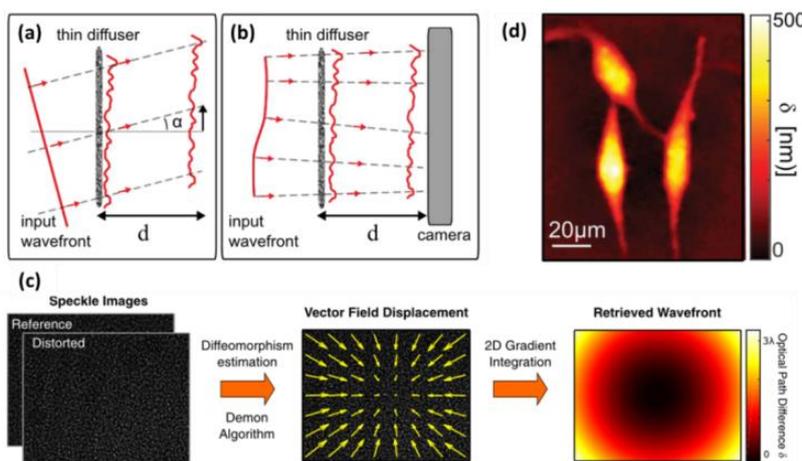


Figure 1: Principle of the thin-diffuser-based wavefront sensor. (a) For a thin diffuser, a tip or tilt angle  $\alpha$  in the impinging wavefront results in a global shift of the speckle pattern by an amount  $\alpha \cdot d$  at a distance  $d$ . (b) For a distorted wavefront, speckle grains are locally shifted. (c) Wavefront reconstruction procedure. (d) Quantitative phase imaging of HeLa cells on a commercial microscope.

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